Notice of References Cited Application/Control No. 10/692,211 Examiner Sean Weinman Applicant(s)/Patent Under Reexamination LIN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
$ \mathbf{x} $	Α	US-5,422,862	06-1995	Wisor, Michael T.	368/10
X	В	US-6,105,142	08-2000	Goff et al.	713/324
\overline{X}	С	US-6,286,063	09-2001	Bolleman et al.	710/62
X	D	US-5,758,172	05-1998	Seo, Seung-Won	713/300
\overline{X}	Е	US-6,134,187	10-2000	Tomiyasu, Yuichi	368/28
X	F	US-6,285,406	09-2001	Brusky, Kevin J.	348/552
\overline{X}	G	US-2003/0045955	03-2003	Janik, Craig M.	700/94
\overline{X}	Н	US-2002/0099550	07-2002	Emerick, John J. JR.	704/270
X	ı	US-6,414,675	07-2002	Shen, Chun-Te	345/211
$ \mathbf{x} $	J	US-5,829,008	10-1998	Podkowa et al.	711/5
\overline{X}	К	US-5,283,819	02-1994	Glick et al.	379/93.01
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.